

## EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
S31	310	257/500.ccls. and @ad<"20030416"	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/01/19 12:25
S33	501	(257/395-397).ccls. and @ad<"20030416"	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/01/19 13:39
S34	1050	257/350.ccls. and @ad<"20030416"	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/01/19 13:51
S35	363	257/E29.26.ccls. and @ad<"20030416"	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/01/19 13:55
S36	1197	semiconductor and (high adj voltage) and (low adj voltage) and ((recess or groove or trench or LOCOS) same (edge or bird\$5 or beak)) and (isolation or insulat\$3)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/01/19 18:11
S37	207	semiconductor and (high adj voltage) and (low adj voltage) and ((recess or groove or trench or LOCOS) same ((edge or bird or beak) with (exten\$4 or protru\$5 or project\$3 or bump\$4))) and (isolation or insulat\$3)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/01/19 18:27
S38	603	semiconductor and (high adj voltage) and (low adj voltage) and ((recess or groove or trench or LOCOS) same (edge or bird or beak)) and (step) and @ad<"20030216"	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/01/19 18:57